

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. SERIAL NO.

107355-00100 10/743,408

APPLICANT

KOMATSU et al.

FILING DATE GROUP

2821

December 23, 2003

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
MA	AA	6,097,345	08/01/2000	WALTON	343	769	11/03/1998
	АВ						
	AC						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRA YES	NSLAT	ION PART.
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Sheet 1 of 1

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MA	AG	2002-252520	9/6/2002	Japan			-		xx
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EXAMINER ALL DE AL	DATE CONSIDERED
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